## REMARKS

This Corrected Response responds to a Final Office Action dated June 19, 2003, in the above-identified patent application. Claims 1-17 are currently pending.

This Corrected Response is substantively the same as the earlier Response filed by applicant on September 10, 2003, except that the page and line numbers provided below have been corrected to correspond to the as-filed specification. Applicant regrets the errors in page and line numbers provided in the earlier response and greatly appreciates the Examiner's willingness to consider this corrected response. As before, no claims have been added or amended. No additional claim fees are required.

In the Final Office Action dated June 19, 2003, the Examiner rejected claims 1-17 under 35 USC §112, first paragraph, as allegedly failing to comply with the written description requirement. The Examiner stated:

"It appears that the specification does not have support for a method or an apparatus for exercising, connecting and optically stimulating components on the integrated circuit simultaneously as recited in [the] recently amended claims. From the specification, it appears that there is only one component on an integrated circuit [that] is exercised, connected to an electrical source and optically stimulated one at a time."

Applicant respectfully disagrees. Applicant's specification does have support for exercising, connecting and optically stimulating components on an integrated circuit simultaneously, as recited in the recently amended claims. In particular, Applicant's specification as originally filed at page 23, line 23 through page 24, line 2: "In the preferred embodiment, probe card 74 extends across the full diameter 12 of wafer 10 so that a single probe card is

used during simultaneous burn-in of each die on the wafer." Applicant's specification as originally filed at page 20, lines 15-18, recites: "In the embodiment shown, individual fiber optic strands 92 [of fiber optic block 70] are densely packed so that bundle 90 extends across the entire diameter of chamber 60 and, therefore, across the entire diameter 12 of wafer 10." Applicant's specification as originally filed at page 24, lines 21-22 recites: "Accordingly, switch 120 is the main control switch for simultaneously providing power to each die on wafer 10." Applicant's specification as originally filed at page 25, lines 1-3 recites: "Utilizing switch 121 to isolate an individual die reduces the problem of one die shorting out the power to all other die on the wafer when all the die are electrically tested in parallel." Applicant's specification as originally filed at page 26, lines 2-4 recites: "Lead 132 is electrically connected to metallic signal source layer 114 so that each of the die on wafer 10 is electrically connected in parallel to the signal layer." Applicant's specification as originally filed at page 30, lines 15-16 recites: The portion of probe card 74 shown in Fig. 11 includes optical switch 120 for simultaneously powering on and off all the die on the wafer."

There is ample support in the specification for a method and an apparatus for exercising, connecting and optically stimulating components on an integrated circuit simultaneously as recited in the recently amended claims. Applicant requests, therefore, that the Examiner withdraw the rejection of claims 1-17 under 35 USC 112, first paragraph.

To allow the Examiner sufficient time to consider this corrected response, applicant herewith submits a Petition for Extension of Time Under 37 C.F.R. §1.136(a) requesting a three-month extension, together with a deposit account authorization for the fee therefore.

There are no other rejections of the claims. In view of the foregoing, applicant requests reconsideration of the application and submits that the application is fully allowable and should be passed to issue.

Respectfully submitted,

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